

MAY 28 2004

SHEET 1 OF 1

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
217623US2SDIVSERIAL NO.  
10/058,099

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hideo ANDO, et al.

FILING DATE

January 29, 2002

GROUP

2615

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

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JUN 01 2004

Technology Center 2600

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
SH	AO	11-238318	08/31/1999	JAPAN		X
SH	AP	8-315551	11/29/1996	JAPAN		X
SH	AQ	9-135412	05/20/1997	JAPAN		X
SH	AR	10-112166	04/28/1998	JAPAN		X
SH	AS	11-162119	06/18/1999	JAPAN		X
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

/Syed Hasan/

Date Considered

12/26/2006

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 217623US2S DIV		SERIAL NO. 10/058,099	
				APPLICANT Hideo ANDO, et al.			
				FILING DATE January 29, 2002		GROUP 2615	
LIST OF REFERENCES CITED BY APPLICANT							
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
SH	AA	5,778,142	7Jul98	TAIRA, et al.	386	97	
SH	AB	5,915,067	22Jun99	NONOMURA, et al.	386	70	
SH	AC	5,999,696	7Dec99	TSUGA, et al.	386	98	
SH	AD	5,999,698	7Dec99	NAKAI, et al.	386	125	
SH	AE	6,088,507	11Jul00	YAMAUCHI, et al.	386	95	
SH	AF	6,094,414	25Jul00	TAIRA, et al.	369	275.3	
SH	AG	6,112,011	29Aug00	HISATOMI	386	98	
SH	AH	6,198,874 B1	6Mar01	KANESHIGE, et al.	386	70	
SH	AI	6,222,806	24Apr01	MORI, et al.	369/533		
	AJ				369/53.32		
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
SH	AO	JP 8-263969	11Oct96	JAPAN	x		
SH	AP	JP 60-236163	22Nov85	JAPAN (English Abstract of Japanese Patent)			x
SH	AQ	JP 58-088978	27May83	JAPAN (English Abstract of Japanese Patent)			x
SH	AR	JP 02-206820	16Aug90	JAPAN (English Abstract of Japanese Patent)			x
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1998-133832 (with English translation)					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				/Syed Hasan/		Date Considered 12/26/2006	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Form PTO 1443 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 217623US-2SDIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE HEREWITH		GROUP To be assigned	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
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	AG						
	AH						
	AI						
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	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
SH	AO	66-68978	6/27/83	Japan			X
SH	AP	60-236163	11/22/85	Japan			X
SH	AQ	2-208820	8/16/90	Japan			X
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner /Syed Hasan/					Date Considered 12/26/2006		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							